100V, 191A, 2.5mΩ N-channel Power SGT MOSFET

JMSH1003VE

Features

- Excellent R_{DS(ON)} and Low Gate Charge
- 100% UIS Tested
- 100% ΔVds Tested
- Halogen-free; RoHS-compliant

Applications

- Load Switch
- PWM Application
- Power Management

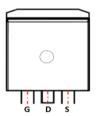
Product Summary

Parameters	Value	Unit
V_{DSS}	100	V
$V_{GS(th)_Typ}$	3.0	V
$I_D(@V_{GS}=10V)$	191	Α
$R_{DS(ON)_Typ}(@V_{GS}=10V$	2.5	mΩ

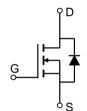




TO-263-3LTop View



Pin Assignment



Schematic Diagram

Ordering Information

Device	Marking	MSL	Form	Package	Reel(pcs)	Per Carton (pcs)
JMSH1003VE-13	SH1003V	3	Tape&Reel	TO-263-3L	800	4000

Absolute Maximum Ratings (@ T_C = 25°C unless otherwise specified)

Symbol	Parameter		Value	Unit
V_{DS}	Drain-to-Source Voltage		100	V
V_{GS}	Gate-to-Source Voltage		±20	V
I-	In Continuous Drain Current		191	Α
I _D	Continuous Diain Current	$T_C = 100$ °C	121	A
I _{DM}	Pulsed Drain Current (1)		Refer to Fig.4	Α
E _{AS}	Single Pulsed Avalanche Energy (2)		1118	mJ
P _D	Power Dissipation	$T_C = 25^{\circ}C$	213	W
	r ower Dissipation	$T_C = 100$ °C	85	V V
T_{J} , T_{STG}	Junction & Storage Temperature Range		-55 to 150	°C

Thermal Characteristics

Symbol	Parameter	Max	Unit
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient ⁽³⁾	34	°C/W
$R_{\theta JC}$	Thermal Resistance, Junction to Case	0.6	C/VV



Electrical Characteristics (T_J = 25°C unless otherwise specified)

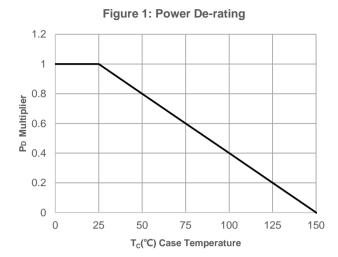
Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit	
Off Cha	Off Characteristics						
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	100	-	-	V	
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 80V, V_{GS} = 0V$	-	-	1.0	μА	
I _{GSS}	Gate-Body Leakage Current	$V_{DS} = 0V, V_{GS} = \pm 20V$	-	-	±100	nA	
On Cha	racteristics						
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2.1	3.0	3.9	V	
R _{DS(ON)}	Static Drain-Source ON-Resistance ⁽⁴⁾	$V_{GS} = 10V, I_{D} = 20A$	-	2.5	3.3	mΩ	
Dynam	ic Characteristics						
R_{g}	Gate Resistance	f = 1MHz	1	1.2	-	Ω	
C _{iss}	Input Capacitance	.,	6105	8547	12821	pF	
C _{oss}	Output Capacitance	$V_{GS} = 0V$, $V_{DS} = 50V$, $f = 1MHz$	843	1180	1770	pF	
C _{rss}	Reverse Transfer Capacitance	1 – 111112	22	31	62	pF	
Q_g	Total Gate Charge		88	123	185	nC	
Q_{gs}	Gate Source Charge	$V_{GS} = 0 \text{ to } 10V$ $V_{DS} = 50V, I_{D} = 20A$	30	42	63	nC	
Q_{gd}	Gate Drain("Miller") Charge	V _{DS} = 30 V, I _D = 20/1	18	25	38	nC	
t _{d(on)}	ing Characteristics Turn-On DelayTime		_	30	_	ns	
t _r	Turn-On Rise Time	$V_{GS} = 10V, V_{DD} = 50V$	-	35	_	ns	
t _{d(off)}	Turn-Off DelayTime	I_{D} = 20A, R_{GEN} = 3 Ω	-	66	-	ns	
t _f	Turn-Off Fall Time		-	28	-	ns	
Body D	liode Characteristics						
I _S	Maximum Continuous Body Diode Forward Current			-	191	А	
I _{SM}	Maximum Pulsed Body Diode Forward Current		-	-	764	Α	
V _{SD}	Body Diode Forward Voltage	$V_{GS} = 0V, I_{S} = 20A$	-		1.2	V	
trr	Body Diode Reverse Recovery Time	1 004 11/11 1004/	61	86	128	ns	
Qrr	Body Diode Reverse Recovery Charge	$I_F = 20A$, di/dt = 100A/us	-	230	-	nC	

Notes:

- 1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature.
- 2. E_{AS} condition: Starting T_J =25C, V_{DD} =50V, V_{GS} =10V, R_G =25ohm, L=3mH, I_{AS} =27.3A, V_{DD} =0V during time in avalanche.
- 3. $\rm R_{\rm \theta JA}$ is measured with the device mounted on a 1inch 2 pad of 2oz copper FR4 PCB.
- 4. Pulse Test: Pulse Width≤300µs, Duty Cycle≤0.5%.



Typical Performance Characteristics



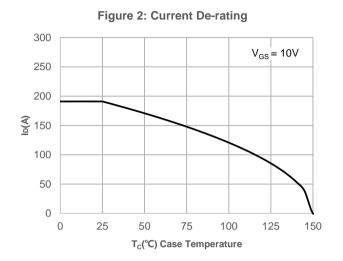
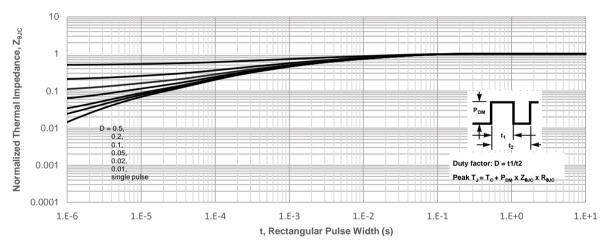
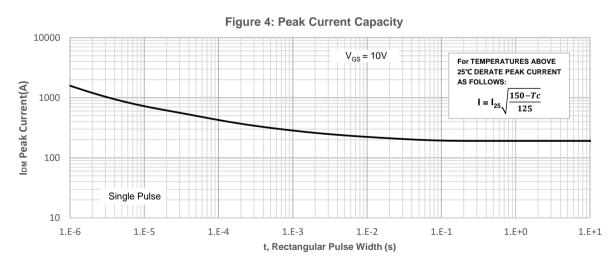


Figure 3: Normalized Maximum Transient Thermal Impedance







Typical Performance Characteristics

Figure 5: Output Characteristics

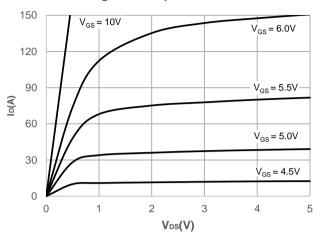


Figure 6: Typical Transfer Characteristics

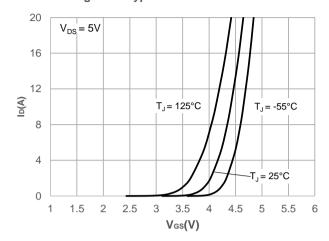


Figure 7: On-resistance vs. Drain Current

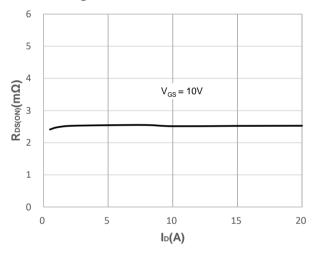


Figure 8: Body Diode Characteristics

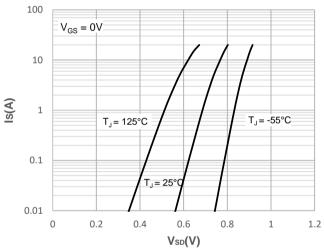


Figure 9: Gate Charge Characteristics

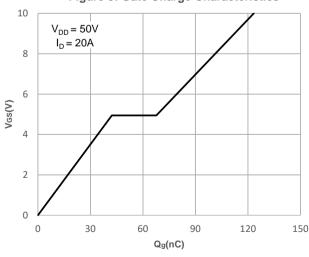
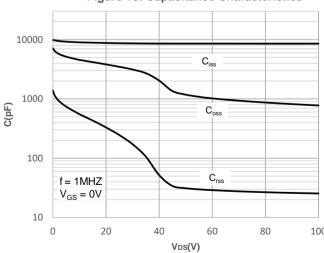


Figure 10: Capacitance Characteristics





Typical Performance Characteristics

Figure 11: Normalized Breakdown voltage vs. Junction Temperature

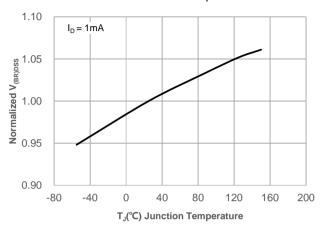


Figure 13: Normalized Threshold Voltage vs.
Junction Temperature

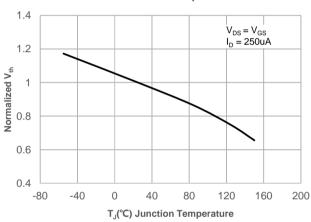


Figure 15: Maximum Safe Operating Area

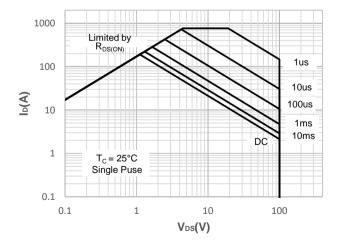
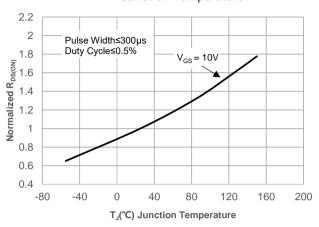
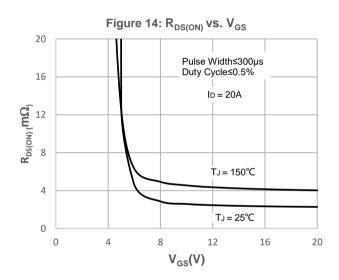


Figure 12: Normalized on Resistance vs.
Junction Temperature







Test Circuit

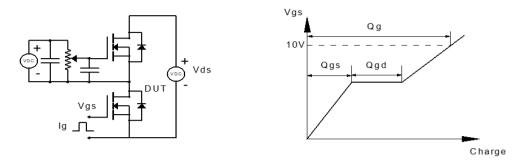


Figure 1: Gate Charge Test Circuit & Waveform

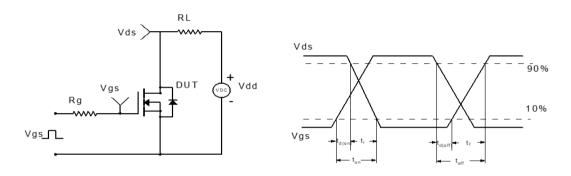


Figure 2: Resistive Switching Test Circuit & Waveform

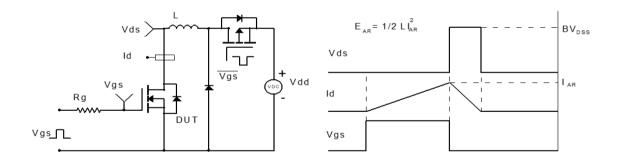


Figure 3: Unclamped Inductive Switching Test Circuit& Waveform

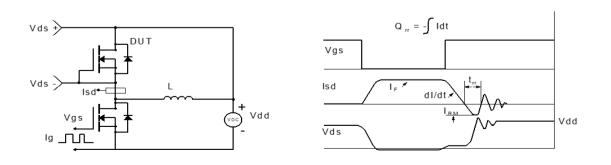
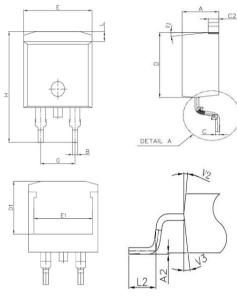


Figure 4: Diode Recovery Test Circuit & Waveform

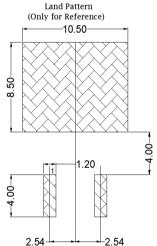


Package Mechanical Data(TO-263 -3L)

Package Outline



SYMBOL		DIMENSIONS	S	
STIVIBUL	MIN	NOM	MAX	
Α	4.3	4.55	4.7	
A2	0		0.15	
В	0.75	0.8	0.85	
С	0.38	0.46	0.55	
C2	1.25	1.3	1.35	
D	8.9	9.3	9.6	
D1	7.4	7.65	7.9	
E	9.9	10.05	10.21	
E1	8.3	8.6	8.9	
G	5.03	5.08	5.13	
Н	14.7	15	15.8	
L2	2.2	2.35	2.5	
L	1.16	1.36	1.61	
V1	5°	7°	9°	
V2	3°	5°	7°	
V3	6°	8°	10°	



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